

In-Situ Phase Diagram Determination of the $\text{HfO}_2\text{-Ta}_2\text{O}_5$ Binary Up to 3000 °C

Scott McCormack^{C, S}

*Materials Science and Engineering, University of Illinois at Urbana Champaign, Urbana-Champaign, IL, U.S.A.
smccorm2@illinois.edu*

Richard Weber

Daniels Court, Materials Development, Arlington Heights, IL, U.S.A.

Denys Kapush and Alexandra Navrotsky

Peter A. Rock Thermochemistry Laboratory and NEAT-ORU, University of California Davis, Davis, CA, U.S.A.

Waltraud Kriven

Materials Science and Engineering, University of Illinois at Urbana Champaign, Urbana-Champaign, IL, U.S.A.

Ceramic equilibrium phase diagrams have proven to be difficult to produce for materials above 1500 °C. We demonstrate that *in-situ* X-ray diffraction on laser-heated, levitated samples can be used to elucidate phase fields. In these experiments, solid spherical samples were suspended and rotated by a gas stream through a conical nozzle levitator, heated by a 400 W CO_2 laser at beamline 6-ID-D of the Advanced Photon Source at Argonne National Laboratory. X-ray diffraction patterns suitable for Rietveld refinement were collected at 100 °C temperature intervals and were used to determine the phase fraction of phases present. The temperature of each phase was determined based on thermal expansion data collected by powder diffraction in conjunction with the Quadrupole Lamp Furnace (QLF) at beamline 33-BM-C. $\text{HfO}_2\text{-Ta}_2\text{O}_5$ was investigated as an example system due to its high melting points and application in refractories and electronics.